

# INPADOCDB

## (INternational PATent DOCumentation DataBase)

<b>Subject Coverage</b>	All areas of science and technology, i.e., all classes of the International Patent Classification			
<b>File Type</b>	Bibliographic			
<b>Features</b>	Thesauri	Cooperative Patent Classification (/CPC), International Patent Classification (/IPC), US National Patent Classification (/NCL)		
	<a href="#">Alerts (SDIs)</a>	Weekly or monthly (Weekly is the default)		
	CAS Registry Number® Identifiers	<input type="checkbox"/>	Page Images	<input type="checkbox"/> STN® AnaVist™ <input type="checkbox"/>
	<a href="#">Keep &amp; Share</a>	<input checked="" type="checkbox"/>	<a href="#">SLART</a>	<input checked="" type="checkbox"/> <a href="#">STN Easy®</a> <input checked="" type="checkbox"/>
	<a href="#">Learning Database</a>	<input checked="" type="checkbox"/>	Structures	<input type="checkbox"/>
<b>Record Content</b>	<ul style="list-style-type: none"> <li>• Bibliographic and family data of patent documents and utility models of more than 100 patent-issuing organizations including the European Patent Office (EPO) and the World Intellectual Property Organization (WIPO)</li> <li>• Legal status data of 77 patent-issuing organizations (53 countries + from 24 countries of the national phases PCT/EP)</li> <li>• Abstracts are provided for 32.5 million records.</li> <li>• First page images are available for the following patent authorities: CH (1944-), DE (1955-), EP (1978-), FR (1961-), GB (1897-), JP (1952-), US (1955-), and WO (1978-)</li> <li>• Calculated expiration dates are provided for granted IP rights for 41 patent authorities, see HELP XPD for details.</li> <li>• Note: The accession number can change due to corrections/updates of patent relevant numbers and codes</li> </ul>			
<b>File Size</b>	<ul style="list-style-type: none"> <li>• More than 83.4 million records (applications) including national patent families with about 100 million publications in more than 52 million international patent families from 1782 to the present (01/18)</li> <li>• More than 220 million legal status data in more than 44 million records from 1968 to the present (05/17)</li> <li>• More than 220 million patent and non-patent citations in more than 25 million patent families are available for 31 authorities from 1943 to the present (05/17)</li> <li>• Citing patent information is available for more than 19.3 million applications</li> </ul>			
<b>Coverage</b>	1782-present			
<b>Updates</b>	Weekly with 130,000-600,000 records and 120,000-500,000 legal status data			
<b>Language</b>	English			
<b>Database Producer</b>	European Patent Office Vienna Sub Office P.O. Box 90 Austria Phone: +43 1 52126-0 Fax: +43 1 52126-5491 Email: <a href="mailto:patentdata@epo.org">patentdata@epo.org</a> Copyright Holder			

**Database Supplier** FIZ Karlsruhe  
STN Europe  
P.O. Box 2465  
76012 Karlsruhe  
Germany  
Phone: +49 7247 808-555  
Fax: +49 7247 808-259  
Email: [helpdesk@fiz-karlsruhe.de](mailto:helpdesk@fiz-karlsruhe.de)  
Copyright Holder

---

- Sources**
- EPO-Patent Information Resource based on the data supplied by the patent offices (INPADOC/DOCDB Service)
  - INPADOC Legal Status Service
- 

- User Aids**
- Online Helps (HELP DIRECTORY lists all help messages available)
  - STNGUIDE
  - More information and additional links see on the INPADOCDB/INPAFAMDB web site  
[http://www.stn-international.com/details\\_inpadocdb.html](http://www.stn-international.com/details_inpadocdb.html)  
[http://www.stn-international.com/inpadocdb\\_inpafamdb\\_handbook.html](http://www.stn-international.com/inpadocdb_inpafamdb_handbook.html)
- 

- Clusters**
- ALLBIB
  - AUTHORS
  - CORPSOURCE
  - HPATENTS
  - PATENTS
- [STN Database Clusters](#) information (PDF)
- 

**Pricing** Enter HELP COST at an arrow prompt.

---

## Search and Display Field Codes

Fields that allow left truncation are indicated by an asterisk (\*).

### Bibliographic Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from title (TI) and abstract (AB) fields)	None or /BI	S TUBULAR HEAT EXCHANG? S ALUM? (S) COAT? S ?MAGNET? S ?METHYL?(T)?AMINO? S (DRILLING(W)PROCESS)/AB	AB, ABDE, ABFR, ABES, ABOL, ABS, TI
Abstract* (contains AB, ABDE, ABES, ABFR, ABOL) (1)	/AB		AB, ABDE, ABES, ABFR, ABOL
Abstract Language (ISO code and text)	/AL	S DUTCH/AL	ALL, ALLO, IMAX, MAX, MAXO
Accession Number	/AN	S 12345678/AN	AN
Application Country (WIPO code and text)	/AC	S WO/AC AND (INLAND(W)STEEL)/PA	AI
Application Date (2)	/AD	S 19840705/AD	AI
Application Kind Code	/AK	S WOW/AK	AI, AIT
Application Kind Code Text	/AIT	S MWA/AIT	AIT
Application Number (4)	/AP	S ZW1981-215/AP	AI
Application Year (2)	/AY	S 1988/AY AND SIEMENS/PAS	AI
Calculated Expiration Date (2)	/XPD	S XPD=AUG 2013	XPD
Calculated Expiration Year (2)	/XPY	S 2010-2011/XPY	XPY
Changes (Indicator for the changes in the last update)	/CHG	S FCL C/CHG	CHG
Citation Category	/CAT	S X/CAT	REN, REP, RE
Cited Application Country	/AC.D	S AT/AC.D	REAI
Cited Application Kind Code	/AK.D	S ATA/AK.D	REAI
Cited Application Number	/AP.D	S AT920000957/AP.D	REAI
Citing Patent Country (WIPO code and text)	/PC.G	S AT/PC.G	CGP
Citing Patent Number	/PN.G	S BG65643/PN.G	CGP
Cooperative Patent Classification	/CPC	S D03D0015-0011/CPC	CPC
CPC, Action Date (2)	/CPC.ACD	S 20130101/CPC.ACD	CPC.TAB
CPC, Combination Set Data (11)	/CPC.CS	S A61K0009/CPC.CS	CPC.TAB
CPC, Keyword Terms	/CPC.KW	S INVENTION/CPC.KW	CPC.TAB
CPC, Version (2)	/CPC.VER	S 20130101/CPC.VER	CPC.TAB
Data Availability	/DAV	S NOT-PRINTED-WITH-GRANT/DAV	DAV
Data in Force (2,4)	/DF	S 20070401/DF	DF
Designated States	/DS	S W JP/DS	DS
Document Type (code and text)	/DT (or /TC)	S U/DT AND UNILEVER/PAS	DT
Entry Date (2,5)	/ED	S L1 AND ED>1 JAN 2007	ED
Entry Date New Patent Family (2)	/EDF	S 20070321/EDF	EDF
Entry Date new publication and/or New Legal Status (2)	/EDLS	S EDLS=20070419	not displayed
Entry Date Patent (2,5)	/EDP	S 20061130/EDP	EDP
Entry Date Priority (2,5)	/EDPR	S 20070401-20070429/EDPR	PRAI
Entry Week (INPADOC) (2,6)	/EW	S 200801/EW	EW
Field Availability	/FA	S L7 AND DS/FA	FA
Filing Country for PCT Application	/AC.WO	S FR/AC.WO	AI
Filing Country for PCT Priorities (WIPO code and text)	/PRC.WO	S DE/PRC.WO	PRAI
Filing Details	/FDT	S DED1/FDT	FDT
International Patent Classification (contains ICM, ICS, ICA, ICI, IPCI, IPCR)	/IPC	S H05B0006-36+NT/IPC S H05B0006-36-H05B0006-44/IPC	IC, ICA, ICI, ICM, ICS, IPCI, IPCR
Inventor	/IN (or /AU)	S NICKOLA RICHARD?/IN	IN
Inventor Address	/INA	S HEIDELBERG/INA	INA
Inventor, Country (WIPO code and text)	/IN.CNY	S GB/IN.CNY	INS

## INPADOCDB

## Bibliographic Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Inventor INPADOC Standard IPC (contains ICM and ICS), Version 1-7 (7)	/INS /IC	S AGARWAL S?/INS S C07H019-16/IC	INS IC
IPC, Action Date IPC, Additional (supplementary) Version 1-7 (7)	/IPC.ACD /ICA	S 13 JAN 2006/IPC.ACD S A61K037-64/ICA	IPC.TAB ICA
IPC, Index (complementary) Version 1-7 (7)	/ICI	S (C12P019-40(L)C12R001:465)/ICI	ICI
IPC, Keyword Terms IPC, Main, Version 1-7 (7)	/IPC.KW /ICM	S INITIAL/IPC.KW S C23C001-08/ICM	IPC.TAB ICM
IPC, Secondary (7)	/ICS	S C12P019-40/ICS	ICS
IPC, Version from IC IPC, Version from IPC	/IC.VER /IPC.VER	S 7/IC.VER AND L5 S 200601/IPC.VER	IC.VER, IC IPC.TAB
Japanese Patent Classification (FI-Terms) Japanese Patent Classification (F-Terms)	/FCL (or /JPC) /FTRM (or /FTERM, or /FTCLA, or /JPCLA)	S A01B0001-24 B/FCL  S 5H030/AA00/FTRM	FCL  FTRM
Language ( ISO code and text) Language of Filing (ISO code and text)	/LA /LAF	S DE/LA S FR/LAF	LA LAF
Locarno Classification Non-Patent Literature XP- Document Number	/LCL /REXP	S 3001/LCL S XP002235691/REXP	LCL REXP
Origin of Citation Other National Classifications (10) Patent Assignee (8)	/SRT /OCL /PA (or /CS)	S EXA/SRT S 81C,27/OCL S INLAND STEEL/PA S BROWN WILLIAMSON/CS	REN, REP, REXP OCL PA
Patent Assignee Address Patent Assignee INPADOC Standard (8)	/PAA /PAS	S US/PAA AND EASTMAN KODAK/PAS S INLAND STEEL CO?/PAS S (BROWN(S)TOBACCO)/PAS	PAA PAS
Patent Assignee, Country Patent Country (WIPO code and text)	/PA.CNY /PC	S GB/PA.CNY S DE/PC AND IBM/PAS AND 1988/PY	PAS PI
Patent Information Publication Type	/PIT	S ARA1/PIT	PIT
Patent Kind Code Patent Number (3) Patent Number/Kind Code	/PK /PN /PNK	S ZWA1/PK S FI990202U/PN S WO2009006253A2/PNK	PI PI PNK
Patent Status Priority Country (WIPO code and text)	/STA /PRC	S GRANTED/STA AND LASER/TI S JP/PRC AND 19880101/PRD	STA PRAI
Priority Date (2) Priority Date, First (2) Priority Kind Code Priority Kind Text Priority Number (3) Priority Year (2) Priority Year, First (2)	/PRD /PRDF /PRK /PRAIT /PRN /PRY /PRYF	S JP/PRC AND 19880101-19880331/PRD S MARCH 2009/PRDF S DEA/PRK S ARA PATENT APPLICATION/PRAIT S US1990-184420/PRN S 1998/PRY AND US/PRC S GB/PC AND 1998/ PRYF	PRAI PRAI PRAI PRAIT PRAI PRAI PRAI
Publication Date (2) Publication Year (2) Reference Count	/PD /PY /REC (or /RE.CNT)	S 19990104/PD S 1999/PY S 8/REC	PI PI REC
Referenced Non-Patent Literature Referenced Patent Country	/REN /RPC (or /PC.D)	S MAYER/REN S WO/RPC	REN RE, REP
Referenced Patent Date	/RPD (or /PD.D)	S 19730919/RPD	REP

## Bibliographic Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Referenced Patent Kind Code	/RPK (or /PK.D)	S EPA/RPK	REP
Referenced Patent Number	/RPN (or /PN.D)	S EP1234567/RPN	REP
Referenced Patent Year	/RPY (or /PY.D)	S 2010/RPY	REP
Search Report Office (WIPO code and text)	/SRO	S CH/SRO	REP
Title*	/TI	S (APPARAT? (S) SMOKE (S) FILTER#)/TI	TI
Title Language (ISO code and text)	/TL	S EN/TL S ENGLISH/TL	TL
Update Date (2)	/UP	S L1 AND UP>20070102	UP
Update Date All Patent Changes (2)	/UPM	S L1 AND 20070222/UPM	not displayed
Update Date Classifications (2)	/UPCC	S L1 AND UPCC>20070222	UPALL
Update Date for combined or split Patent Family (9)	/UPFC	S UPFC=OCT 2009	UPALL
Update Date Legal Status (2)	/UPLS	S UPLS=20070222	LS, LSUP
Update Date New Publication and/or Legal Status Changes of the family (2)	/UPFE	S 20070321/UPFE	UPALL
Update Date of the BIB fields (2)	/UPBB	S L1 AND UPBB>20070222	UPALL
Update Date Patent Family (2) (All Updates)	/UPFA	S 20070329/UPFA	UPALL
Update Date New Patent Family Record (2)	/UPFD	S 20070215/UPFD	UPALL
Update Date Patent Family Legal Status (2)	/UPFL	S 20070321/UPFL	UPALL
Update Date Patent Family Publication Level (2)	/UPFP	S 20070222/UPFP	UPALL
Update Date Patent Family Bibliographic (2)	/UPFB	S 20070215/UPFB AND L7	UPALL
Update Week (INPADOC Week) (2)	/UW	S UW=200641 AND L3	UW
US National Classification, Current	/NCL	S 455289000/NCL	NCL
US National Classification, Current (main)	/NCLM	S 455289000/NCLM	NCL
US National Classification, Current (secondary)	/NCLS	S 455289000/NCLS	NCL
US National Classification, Issued	/INCL	S 548/374.100/NCL S 548374100/NCL	INCL
US National Classification, Issued (main)	/INCLM	S 800320000/NCLM	INCL
US National Classification, Issued (secondary)	/INCLS	S 047/058.10R/NCLS S 04705810R/NCLS	INCL

- (1) This field is available for selected countries and patent publications.  
(2) Numeric search field that may be searched using numeric operators or ranges.  
(3) Either STN or Derwent format may be used.  
(4) For German Utility Models: Advertisement of registration.  
(5) Available since 2007.  
(6) Available since week 200641.  
(7) Search in IPC8 format also available.  
(8) Search with implied (S) proximity is available.  
(9) Available since September 2009.  
(10) Selected coverage for DE, GB, CH, CA, AT, SE, DK, BR, MX, AU, ES, NL.  
(11) No expand is available in this field. A special search edit triggers a search in /CPC combined with (T) proximity and CPC.KW, e.g., S A61K0009/CPC.CS is searched as (A61K0009/CPC (T) COMBINATION SET/CPC.KW)

## Legal Status Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Entry Date New Publication and/or New Legal Status <b>(1)</b>	/EDLS	S EDLS=FEB 2009	not displayed
Entry Week Legal Status	/EWLS	S 200641-200642/EWLS	LS2
Legal Status Basic Index (contains legal status agent (LSAG), legal status free format text (LSFT), legal status inventor (LSIN), legal status patent opponent (LSOP), and legal status patent assignee (LSPA) fields)	/LSBI	S LASER?/LSBI S ANACOMP/LSBI S OPPOSITE/LSBI	LS
Legal Status Code (code and text)	/LSC	S EP111L/LSC	LS
Legal Status Code Category	/LSC2	S NIF/LSC2	LS
Legal Status Code Country (WIPO code and text)	/LSCC	S BE/LSCC	LS
Legal Status Country (WIPO code and text)	/LSCY	S UNITED KINGDOM/LSCY	LS
Legal Status Date in Force <b>(1)</b>	/LSDF	S LSDF=20050109	LS
Legal Status Date INPADOC GAZETTE <b>(1)</b>	/LSD	S LSD=JAN 2002	LS
Legal Status Designated States (WIPO code and text)	/LSDS	S AU/LSDS S AUSTRALIA/LSDS	LS
Legal Status Free Format Text	/LSFT	S TELECOMMUNICATION/LSFT	LS
Legal Status Indicator	/LSCI	S POSITIVE/LSCI AND L3	LS
Legal Status IPC	/LSIC	S 41J320/0/LSIC	LS
Legal Status Patent Assignee <b>(2)</b>	/LSPA	S (MAN CERAMICS)/LSPA	LS
Legal Status Patent Inventor	/LSIN	S MAYER, BERND/LSIN S (MAYER(S)BERND)/LSIN	LS
Legal Status Patent Opponent	/LSOP	S SIEMENS AG/LSOP	LS
Legal Status EP Payment Year <b>(1)</b>	/LSPMY	S 18/LSPMY	LS
Legal Status Publication Country (WIPO code and text)	/LSPC	S CA/LSPC S CANADA/LSPC	LS
Legal Status Publication Date <b>(1)</b>	/LSPD	S LSPD=JAN 1998	LS
Legal Status Publication Kind Code	/LSPK	S ES00/LSPK	LS
Legal Status Publication Number	/LSPN	S EP200212/LSPN	LS
Legal Status Publication Year <b>(1)</b>	/LSPY	S 1999-2000/LSPY	LS
Legal Status Represent./Agent	/LSAG	S (LORENZ AND PHILIPPS)/LSAG	LS
Legal Status Code Text	/LSTX	S CORRECTION/LSTX	LS
Legal Status SPC Number	/LSSPC	S EU/1/00/129/001/LSSPC	LS
Legal Status SPC, Expiry Date <b>(1)</b>	/LSSPC.XD	S LSSPC.XD>2005	LS
Legal Status SPC, Extension Date <b>(1)</b>	/LSSPC.EX	S 20010910/LSSPC.EX	LS
Legal Status SPC, Filing Date <b>(1)</b>	/LSSPC.FD	S 19950101-19961231/LSSPC.FD	LS
Update Legal Status <b>(1)</b>	/UPLS	S 20070208/UPLS	LS, LSUP

**(1)** Numeric search field that may be searched using numeric operators or ranges.

**(2)** Search with implied (S) proximity is available.

## Super Search Fields

Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multfile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group (1)	/APPS	/AP, /PRN	S DE1984-3400052/APPS S 1984DE-3400052/APPS	AI, PRAI
Inventor Group	/INSS	/IN, /INS, /LSIN	S MEIER/INSS	IPC
US National Classification	/NCLALL	/NCL, /INCL	S 901014000/NCLALL	NCL, INCL
Patent Assignee Group	/PASS	/PA, /PAS, /LSPA	S MEIER/PASS	PI
Patent Countries	/PCS	/PC, /DS	S BE/PCS	PI, DS
Patent Number Group (1)	/PATS	/PN, /RPN	S WO1989004114/PATS	PI, REP

(1) Either STN format or Derwent format may be used.

## IPC THESAURUS

The classifications, validity and catchwords for the main headings and subheadings from the current (8<sup>th</sup>) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1-8, use the field code followed by the edition number, e.g., /IPC2 for the 2<sup>nd</sup> edition. Catchwords are included only in the thesauri for the 8<sup>th</sup>, 7<sup>th</sup>, 6<sup>th</sup>, and 5<sup>th</sup> editions.

Code	Content	Examples
ADVANCED (ADV)	Advanced Level Codes for the Core Level IPC Code	E A61K0066-02+ADVANCED/IPC
ALL	All Associated Terms (BT, SELF, NT, RT)	E C01C003-00+ALL/IPC
BRO (MAN)	Complete Class	E C01C+BRO/IPC
BT	Broader Term (SELF, BT)	E C01F001-00+BT/IPC
BTn	Broader Term (SELF, BT) up to the next n levels (n =1,2,...)	E C01F001-21+BT2/IPC
CORE (COR)	Core Codes for the Advanced Level IPC Code	E G08C0019-22+CORE/IPC
ED	Complete title of the SELF term and IPC manual	E C01F001-00+ED/IPC
HIE	Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT)	E C011003-00+HIE/IPC
INDEX	Complete title of the SELF term	E C01F001-00+INDEX/IPC
KT	Keyword Term (catchwords) (SELF, KT)	E CYANOGEN+KT/IPC
NEXT	Next Classification	E C01C001-00+NEXT5/IPC
NT	Narrower Terms (SELF, NT)	E C01C+NT/IPC
NTn	Narrower Terms (SELF, NT) down to the next n levels (n =1,2,...)	E C01C+NT3/IPC
PREV	Previous Code within the same class (SELF, PREV)	E C01C001-12+PREV/IPC
PREV(n)	Previous n classifications within the same class	E C01C001-12+PREV10/IPC
RT (SIB)	Related Terms (SELF, RT)	E C01C003-20+RT/IPC
TI	Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C01F001-00+TI/IPC

## CPC (/CPC) Thesaurus

This thesaurus is available in the /CPC search field. All relationship codes can be used with both the EXPAND and SEARCH commands.

Relationship Code	Content	Search Examples
ALL AUTO (1) BT CODE	All usually required terms (BT, SELF, CODE, DEF) Automatic relationship (BT, SELF, CODE, DEF) Broader terms (BT, SELF) Classification Code (SELF, CODE)	E C12M0001-34H2+ALL/CPC E G01J0003-443+AUTO/CPC E G01J0003-443+BT/CPC E SCRAPER BIASING MEANS+CODE/CPC
DEF HIE	Definition (SELF, DEF) Hierarchy terms (all broader and narrower terms) (BT, SELF, DEF, NT)	E B65G0045-16+DEF/CPC E A01B0001+HIE/CPC
KT MAX NEXT NEXT(n) NT PREV PREV(n) TI	Keyword terms (SELF, KT) All associated terms Next classification within the same class (SELF, NEXT) Next n classification within the same class Narrower terms Previous Code within the same class (SELF, PREV) Previous n classifications within the same class Complete Title of the SELF Term and Broader Terms (BT, SELF)	E LASER+KT/CPC E G01J0003-44B+MAX/CPC E A01B0001-24+NEXT/CPC E A01B0001-24+NEXT3/CPC E G05B0001-04+NT/CPC E G05B0019-418N1+PREV/CPC E G05B0019-418N1+PREV2/CPC E G05B0001-03+TI/CPC

(1) Automatic Relationship is SET OFF. In case of SET REL ON the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

## US National Patent Classification (/NCL, /INCL) Thesaurus

The US National Patent Classification thesaurus is available online in the fields /NCL and /INCL. All relationship codes can be used with both the EXPAND and SEARCH commands.

Relationship Code	Content	Search Examples
ALL AUTO (1) BT CODE DEF HIE KT MAX	All usually required terms (BT, SELF, DEF, NT) Automatic relationship (BT, SELF, DEF, NT) Broader Terms (BT, SELF) Classification Code (SELF, CODE) Definition (SELF, DEF, DEF2, DEF3, DEF4) Hierarchy Terms (BT, SELF, DEF, NT) Keyword Terms (SELF, KT) All associated Terms (BT, SELF, DEF, DEF2, DEF3, DEF4, NT, KT)	E 257E21685+ALL/NCL E 02416300R+AUTO/NCL E 02416300R+BT/NCL E APPAREL+CODE/NCL E G9B031001+DEF/NCL E 23548700+HIE/NCL E APPAREL+KT/NCL E G9B031000+MAX/NCL
NEXT NEXT(n) NT PREV PREV(n) TI	Next classification within the same class Next n classifications within the same class Narrower Terms (SELF, NT) Previous Code within the same class Previous n classifications within the same class Complete title including Broader Terms (SELF, BT, DEF (BT))	E G9B033035+NEXT/NCL E G9B033035+NEXT2/NCL S 257E21685+NT/NCL E 235462260+PREV/NCL E 235462260+PREV3/NCL E 052002110+TI/NCL

(1) Automatic Relationship is SET OFF. In case of SET REL ON the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.



## DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI PI. The fields are displayed or printed in the order requested.

All custom display fields provide the deduplicated content of all publications of a record (national family).

**You can combine all display fields and all display formats with the qualifier .M to display the content for all publications of a record.**

**You can combine all display fields and all display formats with the qualifier .F to display the content for all family members (will be charged as a family display).**

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB	Abstract in English	D AB
ABDE	Abstract in German	D ABDE
ABES	Abstract in Spanish	D ABES
ABEQ (1)	Display of an English equivalent abstract	D ABS
ABFR	Abstract in French	D ABFR
ABOL	Abstract in Other Language	D ABOL
AI (2)	Application Information	D AI
AIT	Application Kind Code Text	D AIT
AN	Accession Number	D AN
CGP	Citing Patent Information	D CGP
CHG	Changes (Indicator for changes in the last update)	D CHG
CPC	Cooperative Patent Classification	D CPC
DAV	Data Availability	D DAV
DF	Date in Force	D DF
DS	Designated States	D DS
DT (TC)	Document Type	D DT
ED	Entry Date	D ED
EDP	Entry Date Patent	D EDP
EW	Entry Week	D EW
FA	Field Availability	D FA
FCL (JPC)	Japanese Patent Classification (FI-Terms)	D FCL
FDT	Filing Details	D FDT
FTRM (FTERM, FTCLA, JPCLA)	Japanese Patent Classification (F-Terms)	D FTRM
FN	Family Number	D FN
GI	Graphic Image	D GI
IC	International Patent Classification (ICM, ICS)	D IC
ICA	IPC, Additional (supplementary)	D ICA
ICI	IPC, Index (complementary)	D ICI
ICM	IPC, Main	D ICM
ICS	IPC, Secondary	D ICS
IN	Inventor	D IN
IN.CNY	Inventor, Country	D INS
INA	Inventor Address	D INA
INCL	US National Classification, Issued	D INCL
INCLM	US National Classification, Issued (main)	D INCL
INCLS	US National Classification, Issued (secondary)	D INCL
INS	Inventor INPADOC Standard	D INS
IPCI	IPC, Initial	D IPCI
IPCR	IPC, Reclassified	D IPCR
LA	Language	D LA
LAF	Language of Filing	D LAF
LCL	Locarno Classification	D LCL
NCL	US National Classification, Current	D NCL
NCLM	US National Classification, Current (main)	D NCL
NCLS	US National Classification, Current (secondary)	D NCL
OCL	Other National Classifications	D OCL
PA (CS)	Patent Assignee	D PA

**DISPLAY and PRINT Formats (cont'd)**

<b>Format</b>	<b>Content</b>	<b>Examples</b>
PAA PA.CNY PAS PI (PN) (2) PIT PNC.G PNK PRAI (PRN) (2) PRAIT REAI REC (RE.CNT) REN (NPL) REP REXP STA TI TL UP UW XPD XPY	Patent Assignee Address Patent Assignee, Country Patent Assignee INPADOC Standard Patent Information Patent Information Publication Type Citing Patent Number Count Patent Number/Kind Code Priority Information Priority Kind Text Referenced Application Information Reference Count Referenced Non-Patent Literature Referenced Patents Non-Patent Literature XP-Document Number Status Title Title Language Update Date Update Week (INPADOC Week) Calculated Expiration Date Calculated Expiration Year	D PAA D PAS D PAS D PI D PIT D PNC.G D PNK D PRAI D PRAIT D REP D REC D REN D REP D REXP D STA D TI D TL D UP D UW D XPD D XPY
ABS (1) ALL (2) ALLG ALLO (2) IALL (2) IALLG BIB (2)  IBIB (2) APPS (2) BRIEF  BRIEFG CPC.TAB IND IPC IPC.TAB LS LS2 LSUP MAX (2) MAXG IMAX (2) IMAXG MAXO (2) MAXO2 (2) PATS (2) PI.PDF  RE SCAN (3)  STD (2) STDG TRIAL (TRI, FREE, SAMPLE, SAM)	AN, AB, ABDE, ABES, ABFR, ABOL, ABEQ BIB, all Abstracts, IND, FA, CHG ALL, plus graphic image ALL, with original data in UTF-8 characters ALL, indented with text labels IALL, plus graphic image AN, ED, EW, UP, UW, FN, UPFC, TI, TL, IN, INS, INA, PA, PAS, PAA, DT, LA , LAF, PI, PIT, DAV, STA, DF, DS, XS, AI, AIT, PRAI, PRAIT, REC, XPD (The default format is BIB.M) BIB, indented with text labels Application Number Group (AI, PRAI) TI, INS, PAS, IPCI, IPCR, CPC, NCL, INCL, FTRM, FCL, LCL, PI, AI, PRAI, abstracts BRIEF, plus graphic image CPC, CPC.KW, CPC.ACD, CPC.VER, in tabular format AN, ED, EW, UP, UW, IPC, CPC, NCL, INCL, FTRM, FCL, LCL, OCL ICM, ICS, ICA, ICI, IPCR, IPCI IPC, IPC.KW, IPC.ACD, IPC.VER, in tabular display AN, UPLS, Legal Status Legal Status, detailed version with display headers Last LS Update ALL.M plus RE, CGP, LS MAX, plus graphic image MAX, indented with text labels IMAX, plus graphic image MAX, with original data in UTF-8 characters MAXO, plus display of special characters in the abstract Patent Number Group (PI, REP) National family PI information plus hyperlinks to the original documents (PDF) in Espacenet Cited References (REP, REXP, REAI, REN) TI latest publication (random display without answer number) BIB, IND STD, plus graphic image TI, IPC, CPC, NCL, INCL, FTRM, FCL, LCL, FA	D ABS D ALL D ALLG D ALLO D IALL D IALLG D BIB  D IBIB D APPS D BRIEF  D BRIEFG D CPC.TAB D IND D IPC D IPC.TAB D LS D LS2 D LSUP D MAX D MAXG D IMAX D IMAXG D MAXO D MAXO2 D PATS D PI.PDF  D RE D SCAN  D STD D STDG D TRIAL

**DISPLAY and PRINT Formats (cont'd)**

Format	Content	Examples
HIT KWIC OCC	Hit term(s) and field(s) Up to 50 words before and after hit term(s) (KeyWord-In-Context) Number of occurrences of hit term(s) and field(s) in which they occur	D HIT D KWIC D OCC

- (1) ABEQ only for records entered or updated after week 200740.
- (2) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.
- (3) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

**FAMILY DISPLAY and PRINT Formats**

Format	Content	Examples
TIPI.F PILS.F (1,4) BIBLS.F (1) CFAM (1) CFAM2 (1) CITN DFAM (1,2) DFAM.AD DFAM.AP DFAM.PD DFAM.PN DFAM.PRD EFAM (1) EFAM.PRD FAM (1) FAM.PRD FAMLS (1)  FAM2 (1) FFAM (1) FFAM.PC (1,3) FFAMG IFAM (1) IFAMG LFAM (1) MFAM (1) MFAMG MFAM.PC (1,3) PICITN SFAM (1)  UPALL	TI + LS for all patent family members PI + LS for all patent family members BIB + LS for all patent family members Condensed family table with publication numbers and dates Condensed family table with PI, AI, PRAI Contains RE + CGP for all patent family member FAM, delimited for post processing DFAM, sorted by Application Date DFAM, sorted by Application Number DFAM, sorted by Patent Date DFAM, sorted by Patent Number DFAM, sorted by Priority Date FAM, but the priority information constitutes the header EFAM, sorted by Priority Date AN, table of patent family information (PI, AI, PRAI) and relationships AN, table of patent family information, sorted by Priority Date Comprises the family table CFAM2 plus a list of all legal status entries, sorted by legal status date LSD AN, table of patent family information, another order STD + LS for each member of the family FFAM for a specified country only FFAM, plus graphic image Combines indented FAM and IMAX.F IFAM, plus graphic image AN, PI, LSUP for all members of a patent family MAX for each family member MFAM, plus graphic image MFAM for a specified country only PI + CITN for all patent member family Display of the EPO 'simple patent family' (SFN) within the INPADOC patent family table Table of update dates (AN, FN, UPFC, UPBB, UPCC, ED, EDP, UPFB, UPFP, UPFD, EDF, UPFL)	D TIPI.F D PILS.F D BIBLS D CFAM D CFAM2 D CITN D DFAM D DFAM.AD D DFAM.AP D DFAM.PD D DFAM.PN D DFAM.PRD D EFAM D EFAM.PRD D FAM D FAM.PRD D FAMLS  D FAM2 D FFAM D FFAM.PC D FFAM.G D IFAM D IFAMG D LFAM D MFAM D MFAMG D MFAM.PC D PICITN D SFAM  D UPALL

- (1) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.
- (2) SET LINE 100 is recommended.
- (3) PC = all countries
- (4) In format PILS legal status is displayed without the information PRI, APP, and PUB.

## FAMILY DISPLAY and PRINT Formats – Weekly SDI

Format	Content	Examples
FFAMED (1) FFAMED.PC (1,2) FFAMUP (1) FFAMUP.PC (1,2) IFAMED (1) IFAMUP (1) LFAMUP (1) LFAMUP.PC (1,2)	STD for new publications and/or LSUP for each updated family FFAMED for a specific country only STD + LS for each updated family FFAMUP for a specific country only Indented FFAMED plus patent family table Indented FFAMUP plus patent family table AN, PI, LSUP for all updated members of a patent family LFAMUP for a specific country only	D FFAMED D FFAMED.PC D FFAMUP D FFAMUP.PC D IFAMED D IFAMUP D LFAMUP D LFAMUP.PC

(1) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.

(2) PC = AR, AT, AU, BE, BR, CA, CH, CN, DE, DK, EP, ES, FI, FR, GB, IT, JP, MX, NL, NO, RU, SE, TW, US, WO

## FAMILY DISPLAY and PRINT Formats – Monthly SDI

Format	Content	Examples
FFAMED4 (1) FFAMUP4 (1) IFAMED4 (1) IFAMUP4 (1) LFAMUP4 (1)	STD for new publications and/or LSUP for each updated family STD + LS for each updated family Indented FFAMED4 plus patent family table Indented FFAMUP4 plus patent family table AN, PI, LSUP for all updated members of a patent family	D FFAMED4 D FFAMUP4 D IFAMED4 D IFAMUP4 D LFAMUP4

(1) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.

## Sorting within the PATENT FAMILY DISPLAY Formats

Format	Content
FAM DFAM EFAM FFAM LFAM CFAM	PRN (Priority Number) PRN (Priority Number) PRN (Priority Number) PN (Patent Number) of the highest level PN (Patent Number) of the highest level AP (Application Number)

You can define the sort parameter in family display formats. Depending on the formats used, options are priority date (.PRD), publication date (.PD), patent number (.AP), application date (.AD). The following combinations are available.

Format	Content
FAM.PRD CFAM.PD DFAM.PRD DFAM.AP DFAM.AD DFAM.PN DFAM.PD EFAM.PRD	Priority Date Publication Date Priority Date Application Number Application Date Patent Number Patent/Publication Date Priority Date

## SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

The SELECT/ANALYZE command extracts terms from all publication levels.

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract in English	AB	Y	Y
Abstract in French	ABFR	Y (2)	Y
Abstract in German	ABDE	Y (2)	Y
Abstract in Other Language	ABOL	Y (2)	Y
Abstract in Spanish	ABES	Y (2)	Y
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Kind Code	AK	Y	Y
Application Kind Code Text	AIT	Y	Y
Application Number	AP (AI)	Y (3)	Y
Application Number Group	APPS	Y (3,4)	N
Application Year	AY	Y	Y
Calculated Expiration Day	XPD	Y	Y
Calculated Expiration Year	XPY	Y	Y
Changes (Indicator for the changes in the last update)	CHG	Y	N
Cited Application Country	AC.D	Y	N
Cited Application Kind Code	AK.D	Y	N
Cited Application Number	AP.D	Y	N
Citing Patent Country	PC.G	Y	N
Citing Patent Number	PN.G	Y	N
Citing Patent Number Count	PNC.G	Y	N
Cooperative Patent Classification	CPC	Y	N
Date in Force	DF	Y	Y
Designated State	DS	Y	N
Document Type	DT (TC)	Y	Y
Entry Date	ED	Y	N
Entry Date Patent	EDP	Y	N
Entry Week	EW	Y	N
International Patent Classification	IC	Y	N
International Patent Classification	IPC	Y	Y
Inventor	IN (AU)	Y	Y
Inventor Address	INA	Y	Y
Inventor Address, Country	IN.CNY	Y	Y
Inventor INPADOC Standard	INS	Y	Y
IPC, Additional (supplementary)	ICA	Y	Y
IPC, Advanced Level Symbols	IPC.A	Y (5)	N
IPC, Advanced Level Symbols for Invention	IPC.AI	Y (5)	N
IPC, Core Level Symbols	IPC.C	Y (5)	N
IPC, Core Level Symbols for Invention	IPC.CI	Y (5)	N
IPC, Index (complementary)	ICI	Y	Y
IPC, Initial	IPCI	Y (5)	N
IPC, Main	ICM	Y	Y
IPC, Reclassified	IPCR	Y (5)	N
IPC, Secondary	ICS	Y	Y
Japanese Patent Classification (F-Terms)	FTRM	Y	N
Japanese Patent Classification (FI-Terms)	FCL	Y	N
Language	LA	Y	Y
Language of Filing	LAF	Y	Y

## INPADOCDB

**SELECT, ANALYZE, and SORT Fields (cont'd)**

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Locarno Classification	LCL	Y	Y
Legal Status Code	LSC	Y	N
Legal Status Code Category	LSC2	Y	N
Legal Status Code Country	LSCC	Y	N
Legal Status Date INPADOC GAZETTE	LSD	Y	N
Legal Status Free Format Text	LSFT	Y	N
Legal Status IPC	LSIC	Y	N
Legal Status Patent Assignee	LSPA	Y	N
Legal Status Patent Inventor	LSIN	Y	N
Legal Status Patent Opponent	LSOP	Y	N
Legal Status EP Payment Year	LSPMY	Y	N
Legal Status Publication Country	LSPC	Y	N
Legal Status Publication Date	LSPD	Y	N
Legal Status Publication Number	LSPN	Y	N
Legal Status Representative/Agent	LSAG	Y	N
Legal Status SPC Number	LSSPC	Y	N
Legal Status SPC, Expiry Date	LSSPC.XD	Y	N
Legal Status SPC, Extension Date	LSSPC.EX	Y	N
Legal Status SPC, Filing Date	LSSPC.FD	Y	N
US National Classification, Current	NCL	Y	Y
US National Classification, Current (main)	NCLM	Y	N
US National Classification, Current (secondary)	NCLS	Y	N
US National Classification, Issued	INCL	Y	N
US National Classification, Issued (main)	INCLM	Y	N
US National Classification, Issued (secondary)	INCLS	Y	N
Occurrence Count of Hit Terms	OCC	N	Y
Other National Classifications	OCL	Y	Y
Patent Assignee	PA (CS)	Y	Y
Patent Assignee Address	PAA	Y	Y
Patent Assignee INPADOC Standard	PAS	Y	Y
Patent Assignee, Country	PA.CNY	Y	Y
Patent Country	PC	Y	Y
Patent Information Publication Type	PIT	Y	Y
Patent Kind Code	PK	Y	Y
Patent Number	PN (PI)	Y (3)	Y
Patent Number/Kind Code	PNK	Y	N
Patent Number Group	PATS	Y (3,6)	Y
Pre-IPC8 Symbols from the ICM and first IPC8 values from 2006 to the present	IPC.F	Y (5)	Y
Priority Country	PRC	Y	Y
Priority Country, First	PRCF	Y	Y
Priority Country, First of PCT Priorities	PRCF.WO	Y	Y
Priority Date	PRD	Y	Y
Priority Date, First	PRDF	Y	Y
Priority Kind Code	PRK	Y	Y
Priority Kind Text	PRAIT	Y	Y
Priority Number	PRN (PRAI)	Y (3)	Y
Priority Year	PRY	Y	Y
Priority Year, First	PRYF	Y (7)	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y	Y
Reference Count	REC (RE.CNT)	Y	N
Referenced Non-Patent Literature	REN	Y	Y
Referenced Non-Patent Literature XP-Document Number	REXP	Y	Y
Referenced Patent Country	RPC (PC.D)	Y	N
Referenced Patent Date	RPD (PD.D)	Y	N
Referenced Patent Kind Code	RPK (PK.D)	Y	N
Referenced Patent Number	RPN (PN.D)	Y	N
Referenced Patent Year	RPY (PY.D)	Y	N
Referenced Patents	REP	Y	Y

**SELECT, ANALYZE, and SORT Fields (cont'd)**

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Title	TI	Y (default)	Y
Title Language	TL	Y	Y
Update Date	UP	Y	N
Update Week	UW	Y	N

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
- (2) Appends /AB to the terms created by SELECT.
- (3) SELECTed and SORTed application, priority and patent numbers are in the format set by the Messenger SET PATENT command, either DERWENT or STN.
- (4) Selects or analyzes AP, PRN, and appends /APPS to the terms created by SELECT.
- (5) Appends /IPC to the terms created by SELECT.
- (6) Selects or analyzes /PN, /RPN with /PATS appended to the terms created by SELECT.
- (7) SELECT or ANALYZE HIT are not valid with this field.

**Update Codes (for SDI also)****Update codes or entry dates associated with records**

Field Name	Search Code	Search Examples	Display Codes
Entry Date	/ED	S L1 AND ED>DEC 2006	ED
Entry Date + Legal Status Update	/EDLS	S EDLS = JAN 2008	not displayed
Entry Date Patent (new record)	/EDP	S 20061026/EDP	EDP, UPALL
Entry Date Priority	/EDPR	S 29 JAN 2009/EDPR	PRAI
Update Date	/UP	S 20070102/UP	LS
Update Legal Status	/UPLS	S 20070222/UPLS	LS
All updates of a record	/UPM	S 20070215/UPM	not displayed

**Update codes or entry dates associated with patent families (1,2)**

Field Name	Search Code	Search Examples	Display Codes
Entry Date new patent family	/EDF	S L1 AND EDF>21 MAR 2007	UPALL
All changes in a patent family	/UPFA	S L1 AND 20070329/UPFA	not displayed
Any change of a bibliographic element in a patent family	/UPFB	S L1 AND 20070215/UPFB	UPALL
Update Date for combined or split Patent Family (3)	/UPFC	S L1 AND UPFC=OCT 2009	UPFC
Entry of a new database record (document) into a patent family (level 1)	/UPFD	S L1 AND 20070215/UPFD	UPALL
Entry of a new publication and changes in legal status	/UPFE	S L1 AND 20070321/UPFE	not displayed
Any change of a legal status in a patent family	/UPFL	S L1 AND 20070321/UPFL	UPALL
Entry of a new publication level into a patent family	/UPFP	S L1 AND 20070222/UPFP	UPALL

- (1) Available since February 2007.
- (2) Special display formats available for monitoring patent families weekly.
- (3) Available since September 2009.

## Sample Records

### DISPLAY MAXG

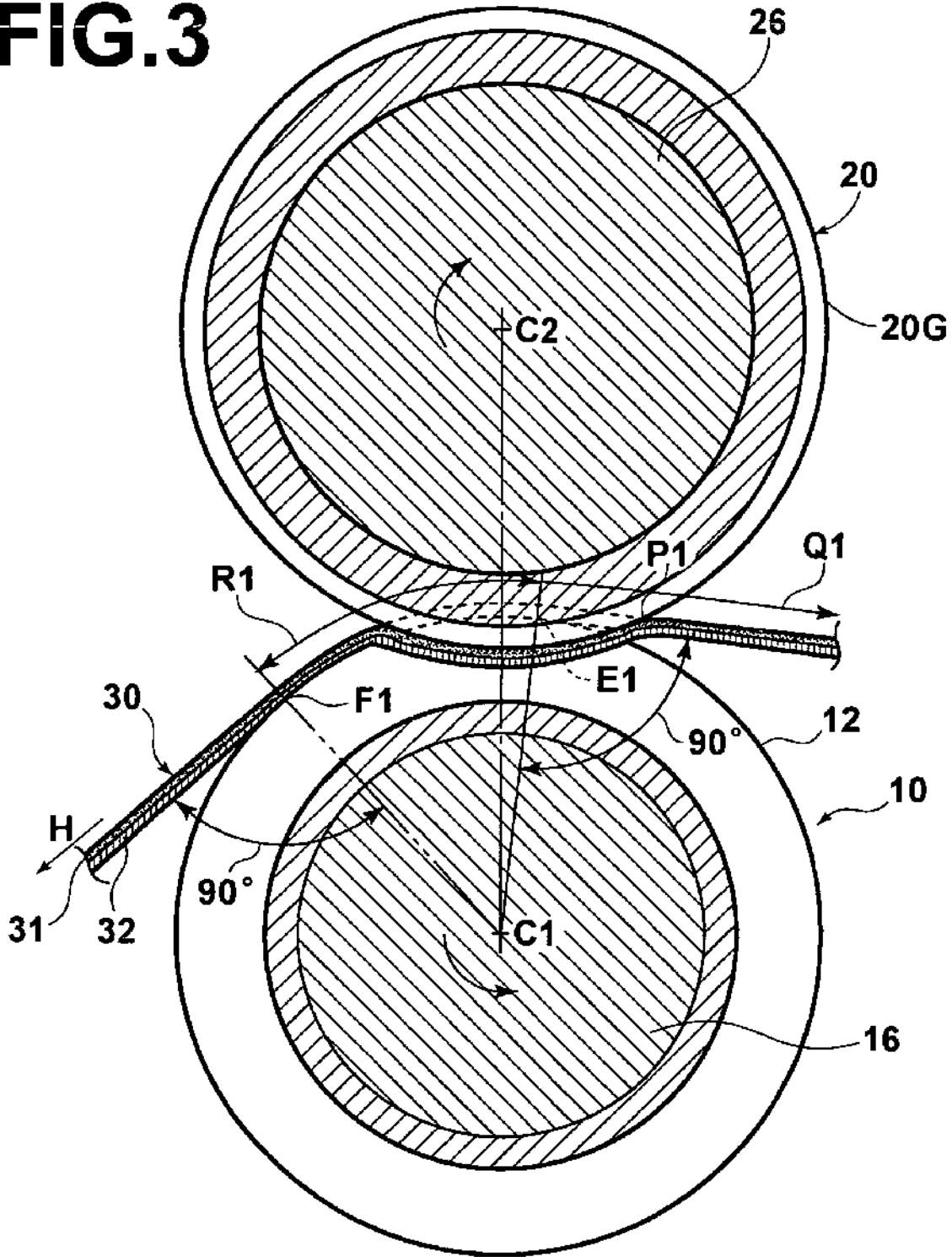
AN 24180089 INPADOCDB UW 201212  
FN 13550763  
TI Verfahren und Vorrichtung zum Schneiden eines beschichteten Blattes.  
Coated sheet cutting method and apparatus.  
Procede et appareil pour la coupe d'une feuille revetue.  
TL German; English; French  
IN KAWAI, HIROKAZU  
INS KAWAI HIROKAZU, JP  
PA FUJI PHOTO FILM CO., LTD.  
PAS FUJI PHOTO FILM CO LTD, JP  
DT Patent  
PI EP 1488896 A1 20041222 English  
PIT EPAL APPLICATION PUBLISHED WITH SEARCH REPORT  
DAV 20041222 examined-printed-without-grant  
STA PRE-GRANT PUBLICATION  
DS R: DE FR GB  
AI EP 2004-13971 A 20040615  
AIT EPA Patent application  
PRAI JP 2003-174783 A 20030619 (JPA, 20070816, Y)  
JP 2003-174784 A 20030619 (JPA, 20070816, Y)  
PRAIT JPA Patent application  
REP JP 2001138285 A (SEA, npl, Cat: Y)  
SONY CORP  
JP 06168444 A (SEA, npl, Cat: Y)  
MATSUSHITA ELECTRIC IND CO LTD  
REXP XP000510813 (SEA, Cat: A)  
REN (1) PATENT ABSTRACTS OF JAPAN vol. 2000, no. 22, 9 March 2001  
(2001-03-09) & JP 2001 138285 A (SONY CORP), 22 May 2001 (2001-05-22)  
(SEA, Cat: Y)  
(2) PATENT ABSTRACTS OF JAPAN vol. 0185, no. 05 (P-1803), 21 September  
1994 (1994-09-21) & JP 6 168444 A (MATSUSHITA ELECTRIC IND CO LTD), 14  
June 1994 (1994-06-14) (SEA, Cat: Y)  
(3) KLEIN H: "LANGSSCHNEIDEN VON BAHNFORMIGEN MATERIALIEN DER  
KREISMESSER-SCHERENSCHNITT UND SEINE OPTIMALE EINSTELLUNG FUR DAS  
LANGSSCHNEIDEN BAHNFORMIGER MATERIALIEN (TEIL 3)" COATING, VERLAG COATING  
THOMAS & CO, CH, vol. 28, no. 5, 1 May 1995 (1995-05-01), pages 176-179,  
XP000510813 ISSN: 0590-8450 (SEA, Cat: A)  
REC 5. THERE ARE 5 CITED REFERENCES (2 PATENT, 3 NON PATENT) AVAILABLE FOR  
THIS RECORD.  
IC.V 7  
ICM B26D001-24  
IPCR B26D0001-24 [I,A]; B26D0007-26 [N,A]  
CPC B26D0001-245; B26D0007-2635; B26D2001-0053  
AB A discoid lower blade and a discoid upper blade, having a sharper knife  
angle compared with that of the lower blade, are arranged such that  
rotational axes thereof are parallel to each other, and portions of the  
blades overlap one another in the direction that the rotational axes  
extend. A sheet with a coating layer on one side is fed through and shear-  
cut between the upper and lower blades in the direction perpendicular to  
the rotational axes, with the surface of the sheet opposite the coating  
layer in contact with a periphery of the lower blade while the blades are  
rotated. When the sheet is shear-cut, a contact start position, where  
contact between the sheet and the upper blade starts, is positioned  
upstream in the feed direction of the sheet but outside a contacting area  
of the sheet, where the sheet contacts the periphery of the lower cutting  
blade. Alternatively, the contact start position starts within the  
contacting area and an overlap between a part of the upper cutting blade



and a part of the lower cutting blade is maintained less than 1.5 mm.  
<IMAGE>.

AL English  
AS EPO  
FA AB; AI; AN; DAV; CPC; DS; DT; ICM; IN; INS; IPC; IPCR; LA; PA; PAS; PI;  
PIT; PRAI; REN; REP; REXP; TI

# FIG.3



## INPADOCDB

EPA1

AN 24180089 INPADOCDB UW 201212  
 FN 13550763  
 TI Verfahren und Vorrichtung zum Schneiden eines beschichteten Blattes.  
 Coated sheet cutting method and apparatus.  
 Procédé et appareil pour la coupe d'une feuille revêtue.  
 TL German; English; French  
 IN KAWAI, HIROKAZU  
 INS KAWAI HIROKAZU, JP  
 PA FUJI PHOTO FILM CO., LTD.  
 PAS FUJI PHOTO FILM CO LTD, JP  
 DT Patent  
 PI EP 1488896 B1 20061004 English  
 PIT EPB1 PATENT SPECIFICATION  
 DAV 20061004 printed-with-grant  
 STA GRANTED  
 DS R: DE FR GB  
 AI EP 2004-13971 A 20040615  
 AIT EPA Patent application  
 PRAI JP 2003-174783 A 20030619 (JPA, 20070816, Y)  
 JP 2003-174784 A 20030619 (JPA, 20070816, Y)  
 PRAIT JPA Patent application  
 XPD 20240615  
 IPCI B26D0001-24 [I,A]  
 IPCR B26D0007-26 [N,A]  
 CPC B26D0001-245; B26D0007-2635; B26D2001-0053  
 FA AI; AN; DAV; CPC; DS; DT; IN; INS; IPC; IPCI; IPCR; LA; PA; PAS; PI; PIT;  
 PRAI; TI; XPD

## LEGAL STATUS

AN 24180089 INPADOCDB  
 20041222 EPAK + DESIGNATED CONTRACTING STATES:  
 EP A1  
 AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IT LI LU  
 MC NL PL PT RO SE SI SK TR  
 20041222 EPAX + EXTENSION OF THE EUROPEAN PATENT TO  
 AL HR LT LV MK  
 20050803 EP17P + REQUEST FOR EXAMINATION FILED  
 20050603  
 EXA Examination, Search Report  
 20050914 EPAKX + PAYMENT OF DESIGNATION FEES  
 DE FR GB  
 20061004 EPAK + DESIGNATED CONTRACTING STATES:  
 EP B1  
 DE FR GB  
 20061004 EPREG REFERENCE TO A NATIONAL CODE  
 GBFG4D + GB: EUROPEAN PATENT GRANTED  
 20061116 EPREF CORRESPONDS TO:  
 DE 602004002620 P 20061116  
 20070314 EPRAP2 TRANSFER OF RIGHTS OF AN EP PUBLICATION  
 FUJIFILM CORPORATION  
 CHG Change of Owner, Inventor, Applicant  
 .....20070315  
 20070411 EPREG REFERENCE TO A NATIONAL CODE  
 GB732E GB: AMENDMENTS TO THE REGISTER IN RESPECT OF CHANGES OF  
 NAME OR CHANGES AFFECTING RIGHTS (SECT. 32/1977)  
 CHG Change of Owner, Inventor, Applicant  
 .....20070419  
 20070420 EPET + FR: TRANSLATION FILED  
 .....20070510

20070912 EP26N + NO OPPOSITION FILED  
20070705  
.....20070914

20070928 EPREG REFERENCE TO A NATIONAL CODE  
FRTP FR: TRANSMISSION OF PROPERTY  
CHG Change of Owner, Inventor, Applicant  
.....20071011

20070928 EPREG REFERENCE TO A NATIONAL CODE  
FRCD FR: CHANGE OF NAME OR COMPANY NAME  
CHG Change of Owner, Inventor, Applicant  
.....20071011

20120731 EPPGFP + POSTGRANT: ANNUAL FEES PAID TO NATIONAL OFFICE  
DE: 20120613  
Payment Year: 09  
.....20120802

20120831 EPPGFP + POSTGRANT: ANNUAL FEES PAID TO NATIONAL OFFICE  
GB: 20120613  
Payment Year: 09  
.....20120906

20120831 EPPGFP + POSTGRANT: ANNUAL FEES PAID TO NATIONAL OFFICE  
FR: 20120619  
Payment Year: 09  
.....20120906

**DISPLAY FAM**

PATENT FAMILY INFORMATION  
AN 24180089 INPADOCDB

+-----PRAI-----+			+-----AI-----+		
JP 2003-174783	A	20030619	CN 2004-10059710	A	20040617
			DE 2004-602004002620	T	20040615
			EP 2004-13971	A	20040615
			JP 2003-174783	A	20030619
			US 2004-868808	A	20040617
JP 2003-174784	A	20030619	CN 2004-10059710	A	20040617
			DE 2004-602004002620	T	20040615
			EP 2004-13971	A	20040615
			JP 2003-174784	A	20030619
			US 2004-868808	A	20040617
+-----AI-----+			+-----PI-----+		
CN 2004-10059710	A	20040617	CN 1572446	A	20050202
DE 2004-602004002620	T	20040615	DE 602004002620	D1	20061116
EP 2004-13971	A	20040615	EP 1488896	A1	20041222
			EP 1488896	B1	20061004
JP 2003-174783	A	20030619	JP 2005007524	A	20050113
JP 2003-174784	A	20030619	JP 2005007525	A	20050113
US 2004-868808	A	20040617	US 20040255743	A1	20041223

2 priorities, 6 applications, 7 publications

## INPADOCDB

## DISPLAY ALL

AN 51399732 INPADOCDB UP 20120614 UW 201224  
 FN 34407383  
 TI Neck fastening for mechanical line-fastening of insulating material and sealing tracks on flat roofs consists of rail with holes and fastenings formed from screws anchored onto rail bottom and supported with head on rail.  
 Kehlbelegung fuer die mechanische Linienbefestigung von Daemmmaterialien und Abdichtungsbahnen auf Flachdaechern.  
 TL English; German  
 PA HARALD ZAHN GMBH  
 PAS ZAHN HARALD GMBH, DE  
 DT Patent  
 PI DE 102005022624 A1 20061123  
 PIT DEAL DOC. LAID OPEN (FIRST PUBLICATION)  
 DAV 20061123 unexamined-printed-without-grant  
 STA PRE-GRANT PUBLICATION  
 AI DE 2005-102005022624 A 20050517  
 AIT DEA Patent application  
 PRAI DE 2005-102005022624 A 20050517 (DEA, Y)  
 PRAIT DEA Patent application  
 IPCI E04D0005-14 [I,A]; E04B0001-74 [I,A]; E04D0003-36 [I,A]  
 CPC E04D0003-3603; E04D0003-3602; E04D0005-146; F16B0013-00; F16B0043-02  
 AB Neck fastening consists of a rail with holes made in the rail bottom and individual fastenings. Fastenings are each formed from a screw (1) which is put in the rail base, supported with its head (3) on the rail and which cuts with its end into the roof bottom or juts into a wall plug anchored into the roof base. From both sides of the hole on the rail narrow positioning edges or noses protrude on which the underside of the screw head lies. When its clamping force is held steady suspended see-saw like between its positioning edges or noses, the rail lies on the underside of the screw head.  
 AL English  
 AS transcript  
 FA AB; AI; AN; DAV; CPC; DT; IPC; IPCI; PA; PAS; PI; PIT; PRAI; TI

## DISPLAY BIB RE

AN 59518659 INPADOCDB ED 20091015 EW 200942 UP 20091022 UW 200943  
 FN 38441986  
 TI Verfahren zur Beschichtung eines metallischen Substrats mit einer Schicht aus niedrig legiertem Stahl.  
 Method to coat a metallic substrate with low alloy steel layer.  
 Procede de revetement d'un substrat metallique avec un revetement a faible alliage d'acier.  
 TL German; English; French  
 IN CHILDS, CHRISTOPHER; MARCHANT, GEOFFREY  
 INS CHILDS CHRISTOPHER, GB; MARCHANT GEOFFREY, GB  
 PA SIEMENS AKTIENGESELLSCHAFT  
 PAS SIEMENS AG, DE  
 DT Patent  
 PI EP-----2108476 A1 20091014 English  
 PIT EPAL APPLICATION PUBLISHED WITH SEARCH REPORT  
 DAV 20091014 examined-printed-without-grant  
 STA PRE-GRANT PUBLICATION  
 DS R: AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI  
 LT LU LV MC MT NL NO PL PT RO SE SI SK TR  
 XS R: AL BA MK RS  
 AI 2008EP-000007060 A 20080409

AIT EPA Patent application  
 PRAI 2008EP-000007060 A 20080409 (EPA, 20091015, Y)  
 PRAIT EPA Patent application  
 REC 6. THERE ARE 6 CITED REFERENCES (5 PATENT, 1 NON PATENT) AVAILABLE FOR THIS RECORD. ALL CITATIONS ARE AVAILABLE IN THE RE FORMAT.  
 REP EP 1835189 A2 (SEA, pat, Cat: X) GEN ELECTRIC, US  
 EP 1898048 A1 (SEA, pat, Cat: A) HITACHI LTD, JP  
 WO 2006111520 A1 (SEA, pat, Cat: A) SIEMENS AG, DE; SHEPHERD ANDREW, GB; WALKER PAUL METHEW, GB  
 US 4300474 A (SEA, pat, Cat: AD) ROLLS ROYCE  
 GB 2052566 A (APP, pat) ROLLS ROYCE  
 REXP XP008053341 (SEA, Cat: Y)  
 REN (1) NOWOTNY S: "BESCHICHTEN, REPARIEREN UND GENERIEREN DURCH PRAEZISIONS-AUFTRAGSCHWEISSEN MIT LASERSTRAHLEN//CLADDING, REPAIR, AND FREEFORMING BY BUILD-UP WELDING USING LASER IRRADIATION" VAKUUM IN FORSCHUNG UND PRAXIS, WILEY-VCH, WEINHEIM, DE, vol. 14, no. 1, 1 February 2002 (2002-02-01), pages 33-37, XP008053341 ISSN: 0947-076X (SEA, Cat: Y)  
 REC 6. THERE ARE 6 CITED REFERENCES (5 PATENT, 1 NON PATENT) AVAILABLE FOR THIS RECORD.

**In North America**

CAS  
 STN North America  
 P.O. Box 3012  
 Columbus, Ohio 43210-0012 U.S.A.  
 CAS Customer Center:  
 Phone: 800-753-4227 (North America)  
 614-447-3700 (worldwide)  
 Fax: 614-447-3751  
 Email: help@cas.org  
 Internet: www.cas.org

**In Europe**

FIZ Karlsruhe  
 STN Europe  
 P.O. Box 2465  
 76012 Karlsruhe  
 Germany  
 Phone: +49-7247-808-555  
 Fax: +49-7247-808-259  
 Email: helpdesk@fiz-karlsruhe.de  
 Internet: www.stn-international.com

**In Japan**

JAICI (Japan Association for International Chemical Information)  
 STN Japan  
 Nakai Building  
 6-25-4 Honkomagome, Bunkyo-ku  
 Tokyo 113-0021, Japan  
 Phone: +81-3-5978-3601 (Technical Service)  
 +81-3-5978-3621 (Customer Service)  
 Fax: +81-3-5978-3600  
 Email: support@jaici.or.jp (Technical Service)  
 customer@jaici.or.jp (Customer Service)  
 Internet: www.jaici.or.jp